

Testing the Choi-algorithm (patent 5)

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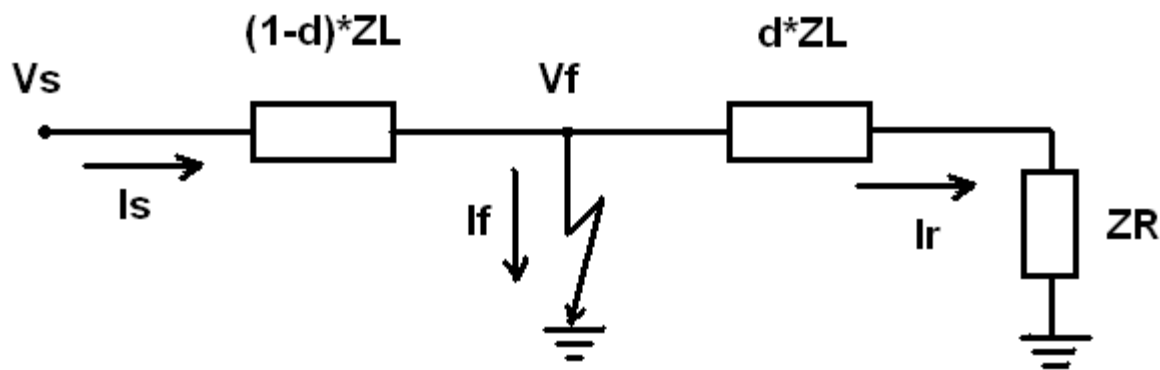
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1. IMPLEMENTING THE PATENTED ALGORITHM IN MATHCAD

1.1. DEFINING A RADIAL TEST FEEDER AND CALCULATING THE FAULT CURRENTS



Fault Location

$$d := 0.5$$

Source S Voltage

$$es := 7071$$

Positive Sequence Line Impedance

$$Z1L := 10 + 13i$$

Line impedances copied from Creelman case

Zero Sequence Line Impedance

$$Z0L := 30 + 39i$$

Load R Positive Sequence Impedance

$$Z1R := 200 + 30i$$

Load R is set to correspond "normal" distribution network load

Load R Zero Sequence Impedance

$$Z0R := 0$$

Fault Impedances

$$INF := 10^{10}$$

$$ZFA := 0 + j \cdot 0$$

$$ZFB := INF + j \cdot 0$$

$$ZFC := INF + j \cdot 0$$

$$ZFG := 0$$

Fault resistance is set to 0 (this should be the easiest fault to locate)

CONSTANTS

$$a := -0.5 + j \cdot 0.8660254$$

$$\text{BAL} := \begin{pmatrix} 1 \\ a^2 \\ a \end{pmatrix} \quad \text{one} := \begin{pmatrix} 1 & 0 & 0 \\ 0 & 1 & 0 \\ 0 & 0 & 1 \end{pmatrix} \quad \text{zero} := \begin{pmatrix} 0 & 0 & 0 \\ 0 & 0 & 0 \\ 0 & 0 & 0 \end{pmatrix}$$

Three phase voltages at S

$$Vs := es \cdot \text{BAL}$$

$$Vs = \begin{pmatrix} 7.071 \times 10^3 \\ -3.535 \times 10^3 - 6.124i \times 10^3 \\ -3.535 \times 10^3 + 6.124i \times 10^3 \end{pmatrix}$$

Conversion of positive sequence and zero sequence impedances to Self and Mutual impedances

$$z_s(z_0, z_1) := \frac{2 \cdot z_1 + z_0}{3} \quad z_m(z_0, z_1) := \frac{z_0 - z_1}{3}$$

Conversion Matrix Format

$$Z(z_0, z_1) := \begin{pmatrix} z_s(z_0, z_1) & z_m(z_0, z_1) & z_m(z_0, z_1) \\ z_m(z_0, z_1) & z_s(z_0, z_1) & z_m(z_0, z_1) \\ z_m(z_0, z_1) & z_m(z_0, z_1) & z_s(z_0, z_1) \end{pmatrix}$$

Conversion

$$Z_L := Z(Z_{0L}, Z_{1L}) \quad Z_R := Z(Z_{0R}, Z_{1R})$$

$$Z_L = \begin{pmatrix} 16.667 + 21.667i & 6.667 + 8.667i & 6.667 + 8.667i \\ 6.667 + 8.667i & 16.667 + 21.667i & 6.667 + 8.667i \\ 6.667 + 8.667i & 6.667 + 8.667i & 16.667 + 21.667i \end{pmatrix} \quad Z_R = \begin{pmatrix} 133.333 + 20i & -66.667 - 10i & -66.667 - 10i \\ -66.667 - 10i & 133.333 + 20i & -66.667 - 10i \\ -66.667 - 10i & -66.667 - 10i & 133.333 + 20i \end{pmatrix}$$

Pre-fault conditions:

$$Z_{PRE} := Z_L + Z_R \quad Z_{PRE} = \begin{pmatrix} 150 + 41.667i & -60 - 1.333i & -60 - 1.333i \\ -60 - 1.333i & 150 + 41.667i & -60 - 1.333i \\ -60 - 1.333i & -60 - 1.333i & 150 + 41.667i \end{pmatrix}$$

$$IPRE := Z_{PRE}^{-1} \cdot (Vs) \quad IPRE = \begin{pmatrix} 32.316 - 6.617i \\ -21.889 - 24.678i \\ -10.428 + 31.295i \end{pmatrix}$$

$$I_a := IPRE_0 \quad |I_a| = 32.987$$

$$I_b := IPRE_1 \quad |I_b| = 32.987$$

$$I_c := IPRE_2 \quad |I_c| = 32.987$$

Line Impedance to the Fault

$$Z_{SS} := (1 - d) \cdot Z_L$$

$$Z_{RR} := d \cdot Z_L + Z_R$$

System Part of the Impedance Matrix

ZTOP := augment(augment(ZSS, zero), one)

$$ZTOP = \begin{pmatrix} 8.333 + 10.833i & 3.333 + 4.333i & 3.333 + 4.333i & 0 & 0 & 0 & 1 & 0 & 0 \\ 3.333 + 4.333i & 8.333 + 10.833i & 3.333 + 4.333i & 0 & 0 & 0 & 0 & 1 & 0 \\ 3.333 + 4.333i & 3.333 + 4.333i & 8.333 + 10.833i & 0 & 0 & 0 & 0 & 0 & 1 \end{pmatrix}$$

ZMID := augment(augment(zero, ZRR), one)

$$ZMID = \begin{pmatrix} 0 & 0 & 0 & 141.667 + 30.833i & -63.333 - 5.667i & -63.333 - 5.667i & 1 & 0 & 0 \\ 0 & 0 & 0 & -63.333 - 5.667i & 141.667 + 30.833i & -63.333 - 5.667i & 0 & 1 & 0 \\ 0 & 0 & 0 & -63.333 - 5.667i & -63.333 - 5.667i & 141.667 + 30.833i & 0 & 0 & 1 \end{pmatrix}$$

ZSYS := stack(ZTOP, ZMID)

$$ZSYS = \begin{pmatrix} 8.333 + 10.833i & 3.333 + 4.333i & 3.333 + 4.333i & 0 & 0 & 0 & 1 & 0 & 0 \\ 3.333 + 4.333i & 8.333 + 10.833i & 3.333 + 4.333i & 0 & 0 & 0 & 0 & 1 & 0 \\ 3.333 + 4.333i & 3.333 + 4.333i & 8.333 + 10.833i & 0 & 0 & 0 & 0 & 0 & 1 \\ 0 & 0 & 0 & 141.667 + 30.833i & -63.333 - 5.667i & -63.333 - 5.667i & 1 & 0 & 0 \\ 0 & 0 & 0 & -63.333 - 5.667i & 141.667 + 30.833i & -63.333 - 5.667i & 0 & 1 & 0 \\ 0 & 0 & 0 & -63.333 - 5.667i & -63.333 - 5.667i & 141.667 + 30.833i & 0 & 0 & 1 \end{pmatrix}$$

Building the voltage Vector:

null := (0 0 0)

E := stack(Vs, null^T, null^T)

TS := augment(augment(one, zero), zero)

TR := augment(augment(zero, one), zero)

TVF := augment(augment(zero, zero), one)

Building Fault Part of the Impedance Matrix:

ZFAG := ZFA + ZFG

ZFAG = 0

ZFBG := ZFB + ZFG

ZFBG = 1×10^{10}

ZFCG := ZFC + ZFG

ZFCG = 1×10^{10}

$$ZF := \begin{pmatrix} ZFAG & ZFG & ZFG \\ ZFG & ZFBG & ZFG \\ ZFG & ZFG & ZFCG \end{pmatrix}$$

$$ZF = \begin{pmatrix} 0 & 0 & 0 \\ 0 & 1 \times 10^{10} & 0 \\ 0 & 0 & 1 \times 10^{10} \end{pmatrix}$$

FABCG := augment(augment(-ZF, -ZF), one)

ZABCG := stack(ZSYS, FABCG)

YABCG := ZABCG⁻¹

Fault Currents:

IABCG := YABCG·E

S - End Fault Currents:

IS := TS·IABCG

R - End Fault Currents:

IR := TR·IABCG

VF fault voltages:

VF := TVF·IABCG

$$IABCG = \begin{pmatrix} 379.553 - 488.938i \\ -85.878 + 70.604i \\ -74.416 + 126.578i \\ 58.964 - 94.574i \\ 85.878 - 70.604i \\ 74.416 - 126.578i \\ 0 \\ -4.642 \times 10^3 - 5.896i \times 10^3 \\ -4.336 \times 10^3 + 5.997i \times 10^3 \end{pmatrix}$$

$$IS = \begin{pmatrix} 379.553 - 488.938i \\ -85.878 + 70.604i \\ -74.416 + 126.578i \end{pmatrix}$$

$$IR = \begin{pmatrix} 58.964 - 94.574i \\ 85.878 - 70.604i \\ 74.416 - 126.578i \end{pmatrix}$$

$$VF = \begin{pmatrix} 0 \\ -4.642 \times 10^3 - 5.896i \times 10^3 \\ -4.336 \times 10^3 + 5.997i \times 10^3 \end{pmatrix}$$

Line Fault Currents from S Bus

I_{asf} := IS₀ |I_{asf}| = 618.968

I_{bsf} := IS₁ |I_{bsf}| = 111.175

I_{csf} := IS₂ |I_{csf}| = 146.833

Line Fault Voltages at S Bus

V_{af} := V_{s0} |V_{af}| = 7.071 × 10³

V_{bf} := V_{s1} |V_{bf}| = 7.071 × 10³

V_{cf} := V_{s2} |V_{cf}| = 7.071 × 10³

1.2. IMPLEMENTING THE PATENTED ALGORITHM

Initial assumptions:

- Faulted phase is known (a)

- Phase voltage (V_{sa}) during the fault is measured

$$V_{sa} := V_{af}$$

$$V_{sa} = 7.071 \times 10^3$$

- Phase currents (I_{sabc}) during the fault are measured

$$I_{sabc} := IS$$

$$I_{sa} := IS_0$$

$$I_{sb} := IS_1$$

$$I_{sc} := IS_2$$

$$I_{sabc} = \begin{pmatrix} 379.553 - 488.938i \\ -85.878 + 70.604i \\ -74.416 + 126.578i \end{pmatrix}$$

Line and load parameters needed in patented algorithm:

$$Z_{laa} := ZL_{0,0}$$

$$Z_{laa} = 16.667 + 21.667i$$

$$Z_{lab} := ZL_{0,1}$$

$$Z_{lab} = 6.667 + 8.667i$$

$$Z_{lac} := ZL_{0,2}$$

$$Z_{lac} = 6.667 + 8.667i$$

$$Z_{raa} := ZR_{0,0}$$

$$Z_{raa} = 133.333 + 20i$$

$$Z_{rab} := ZR_{0,1}$$

$$Z_{rab} = -66.667 - 10i$$

$$Z_{rac} := ZR_{0,2}$$

$$Z_{rac} = -66.667 - 10i$$

Defining C1 and C2:

$$C1 := Z_{laa} \cdot I_{sa} + Z_{lab} \cdot I_{sb} + Z_{lac} \cdot I_{sc}$$

$$C1 = 1.414 \times 10^4$$

$$C2 := Z_{raa} \cdot I_{sa} + Z_{rab} \cdot I_{sb} + Z_{rac} \cdot I_{sc}$$

$$C2 = 7.304 \times 10^4 - 6.914i \times 10^4$$

Defining ar, ai, br, bi, cr, ci, dr and di:

$$ar := \text{Re}(C1 \cdot Z_{laa})$$

$$ar = 2.357 \times 10^5$$

$$ai := \text{Im}(C1 \cdot Z_{laa})$$

$$ai = 3.064 \times 10^5$$

$$br := \text{Re}(V_{sa} \cdot Z_{laa} - C1 \cdot Z_{laa} + C1 \cdot Z_{raa})$$

$$br = 1.768 \times 10^6$$

$$bi := \text{Im}(V_{sa} \cdot Z_{laa} - C1 \cdot Z_{laa} + C1 \cdot Z_{raa})$$

$$bi = 1.296 \times 10^5$$

$$cr := \text{Re}[Z_{raa} \cdot (V_{sa} - C1)]$$

$$cr = -9.428 \times 10^5$$

$$ci := \text{Im}[Z_{raa} \cdot (V_{sa} - C1)]$$

$$ci = -1.414 \times 10^5$$

$$dr := \text{Re}(V_{sa} - C1 - C2) \quad dr = -8.011 \times 10^4$$

$$di := \text{Im}(V_{sa} - C1 - C2) \quad di = 6.914 \times 10^4$$

Defining second degree polynomial coefficients (a, b and c):

$$aa := ar - \frac{dr}{di} \cdot ai \quad aa = 5.907 \times 10^5$$

$$bb := br - \frac{dr}{di} \cdot bi \quad bb = 1.918 \times 10^6$$

$$cc := cr - \frac{dr}{di} \cdot ci \quad cc = -1.107 \times 10^6$$

Solving the polynomial:

$$d1 := \frac{-bb + \sqrt{bb^2 - 4 \cdot aa \cdot cc}}{2 \cdot aa} \quad d2 := \frac{-bb - \sqrt{bb^2 - 4 \cdot aa \cdot cc}}{2 \cdot aa}$$

$$d1 = 0.5$$

Accepted

$$d2 = -3.747$$

Discarded (negative fault distance not possible)

Actual fault distance is 1-d1

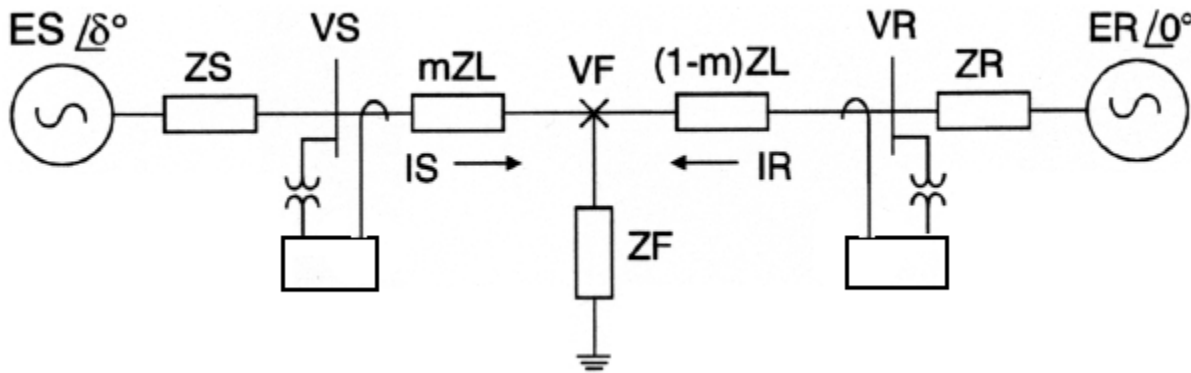
$$1 - d1 = 0.5$$

The calculated fault distance was correct. This proves that the algorithm works (at least in theory)

The algorithm gives correct results with all values of d in range [0,1[and with all realistic fault resistance values

2. TESTING THE PATENTED METHOD WITH IDEAL 2-SOURCE DATA

2.1. DEFINING THE NETWORK AND CALCULATING THE FAULT CURRENTS



INPUT DATA

$\delta := 0.001$ **Voltage Phase Angle**

$es := 10000 \cdot e^{j \cdot \delta \cdot \text{deg}}$ **Source S Voltage**

$er := 0$ **Source R Voltage**

$Z1R := 0.42 + 0.5i$ **Source R Positive Sequence Impedance**

$Z0R := 0$ **Source R Zero Sequence Impedance**

$Z1S := 0.042 + 0.513i$ **Source S Positive Sequence Impedance**

$Z0S := 0.013 + 1.225i$ **Source S Zero Sequence Impedance**

$Z1L := 10 + 13i$ **Positive Sequence Line Impedance**

$Z0L := 30 + 39i$ **Zero Sequence Line Impedance**

Fault Location

$M := 0.5$

Fault Resistance

$ZFG := 0$

Three phase voltages at S and R

$ES := es \cdot \text{BAL}$

$ER := er \cdot \text{BAL}$

Calculating the impedance matrices

$$ZS := Z(Z0S, Z1S)$$

$$ZL := Z(Z0L, Z1L)$$

$$ZR := Z(Z0R, Z1R)$$

Source and Line Impedances to the Fault

$$\underline{ZSS} := ZS + M \cdot ZL$$

$$\underline{ZRR} := ZR + (1 - M) \cdot ZL$$

Build System Part of the Impedance Matrix

$$ZTOP := \text{augment}(\text{augment}(\underline{ZSS}, \text{zero}), \text{one})$$

$$ZMID := \text{augment}(\text{augment}(\text{zero}, \underline{ZRR}), \text{one})$$

$$ZSYS := \text{stack}(ZTOP, ZMID)$$

Pre-fault conditions:

$$\underline{ZPRE} := ZS + ZL + ZR$$

$$\underline{IPRE} := \underline{ZPRE}^{-1} \cdot (ES - ER)$$

Pre_fault voltage at S end

$$VSP := ES - ZS \cdot \underline{IPRE}$$

Build the voltage Vector

$$E := \text{stack}(\text{stack}(ES, ER), \text{null}^T)$$

$$TS := \text{augment}(\text{augment}(\text{one}, \text{zero}), \text{zero})$$

$$TR := \text{augment}(\text{augment}(\text{zero}, \text{one}), \text{zero})$$

Building Fault Part of the Impedance Matrix:

$$\underline{ZFAG} := ZFA + ZFG$$

$$\underline{ZFBG} := ZFB + ZFG$$

$$\underline{ZFCG} := ZFC + ZFG$$

$$ZF := \begin{pmatrix} \underline{ZFAG} & ZFG & ZFG \\ ZFG & \underline{ZFBG} & ZFG \\ ZFG & ZFG & \underline{ZFCG} \end{pmatrix}$$

FABCG := augment(augment(-ZF, -ZF), one)

FINAL Z MATRIX

ZABCG := stack(ZSYS, FABCG)

YABCG := ZABCG⁻¹

Fault Currents:

IABCG := YABCG·E

S - End Fault Currents:

IS := TS·IABCG

R - End Fault Currents:

IR := TR·IABCG

S - End Voltages

VS := ES - ZS·IS

Line Prefault Load Currents from S Bus

I_a := IPRE₀ |I_a| = 571.832

I_b := IPRE₁ |I_b| = 571.832

I_c := IPRE₂ |I_c| = 571.832

Line Prefault Voltages at S Bus

V_a := VSP₀ |V_a| = 9.752 × 10³

V_b := VSP₁ |V_b| = 9.752 × 10³

V_c := VSP₂ |V_c| = 9.752 × 10³

Line Fault Currents from S Bus

I_{asf} := IS₀ |I_{asf}| = 929.021

I_{bsf} := IS₁ |I_{bsf}| = 573.339

I_{csf} := IS₂ |I_{csf}| = 574.148

Line Fault Currents from R Bus

$$\begin{aligned} I_{arf} &:= IR_0 & |I_{arf}| &= 215.693 \\ I_{brf} &:= IR_1 & |I_{brf}| &= 573.339 \\ I_{crf} &:= IR_2 & |I_{crf}| &= 574.148 \end{aligned}$$

Line Fault Voltages at S Bus

$$\begin{aligned} \underline{V}_{af} &:= VS_0 & |V_{af}| &= 9.53 \times 10^3 \\ \underline{V}_{bf} &:= VS_1 & |V_{bf}| &= 9.827 \times 10^3 \\ \underline{V}_{cf} &:= VS_2 & |V_{cf}| &= 9.74 \times 10^3 \end{aligned}$$

Generating digital signals of Voltage and Current of the Simulation 4 Cycles with 7680 samples per second

$$\begin{aligned} k &:= 0..511 \\ \text{delT} &:= 0.0001302 \\ V_{an_k} &:= |VSP_0| \cdot \sin(2 \cdot \pi \cdot 60 \cdot k \cdot \text{delT} + \arg(VSP_0)) \\ T1_k &:= k \cdot \text{delT} \\ T2_k &:= 512 \cdot \text{delT} + k \cdot \text{delT} \\ T3_k &:= 1024 \cdot \text{delT} + k \cdot \text{delT} \\ V_{bn_k} &:= |VSP_1| \cdot \sin(2 \cdot \pi \cdot 60 \cdot k \cdot \text{delT} + \arg(VSP_1)) \\ V_{cn_k} &:= |VSP_2| \cdot \sin(2 \cdot \pi \cdot 60 \cdot k \cdot \text{delT} + \arg(VSP_2)) \\ \underline{V}_{af_k} &:= |VS_0| \cdot \sin(2 \cdot \pi \cdot 60 \cdot k \cdot \text{delT} + \arg(VS_0)) \\ \underline{V}_{bf_k} &:= |VS_1| \cdot \sin(2 \cdot \pi \cdot 60 \cdot k \cdot \text{delT} + \arg(VS_1)) \\ \underline{V}_{cf_k} &:= |VS_2| \cdot \sin(2 \cdot \pi \cdot 60 \cdot k \cdot \text{delT} + \arg(VS_2)) \\ I_{an_k} &:= |IPRE_0| \cdot \sin(2 \cdot \pi \cdot 60 \cdot k \cdot \text{delT} + \arg(IPRE_0)) \\ I_{bn_k} &:= |IPRE_1| \cdot \sin(2 \cdot \pi \cdot 60 \cdot k \cdot \text{delT} + \arg(IPRE_1)) \\ I_{cn_k} &:= |IPRE_2| \cdot \sin(2 \cdot \pi \cdot 60 \cdot k \cdot \text{delT} + \arg(IPRE_2)) \\ I_{af_k} &:= |IS_0| \cdot \sin(2 \cdot \pi \cdot 60 \cdot k \cdot \text{delT} + \arg(IS_0)) \\ I_{bf_k} &:= |IS_1| \cdot \sin(2 \cdot \pi \cdot 60 \cdot k \cdot \text{delT} + \arg(IS_1)) \\ I_{cf_k} &:= |IS_2| \cdot \sin(2 \cdot \pi \cdot 60 \cdot k \cdot \text{delT} + \arg(IS_2)) \end{aligned}$$

Let us make Normal (4 cycle)+ Fault (4 cycle) +Normal (4 cycle)

$$\text{Seg1} := \text{augment}(T1, I_{an}, I_{bn}, I_{cn}, V_{an}, V_{bn}, V_{cn})$$

$$\text{Seg2} := \text{augment}(T2, I_{af}, I_{bf}, I_{cf}, V_{af}, V_{bf}, V_{cf})$$

Seg3 := augment(T3, Ian, Ibn, Icn, Van, Vbn, Vcn)

Final := stack(Seg1, Seg2, Seg3)

$\underline{T} := \text{Final}^{(0)}$ $\underline{Ia} := \text{Final}^{(1)}$ $\underline{Ib} := \text{Final}^{(2)}$ $\underline{Ic} := \text{Final}^{(3)}$ $\underline{Va} := \text{Final}^{(4)}$ $\underline{Vb} := \text{Final}^{(5)}$ $\underline{Vc} := \text{Final}^{(6)}$

Ir := Ia + Ib + Ic

Vr := Va + Vb + Vc

$\underline{m} := \text{length}(Va)$

window := 128

wind := window - 1

dd := $0 \dots \frac{m}{\text{window}} - 1$

kk := $0 \dots m - \text{window}$

k := $0 \dots \frac{m - \text{window}}{8}$

$k0 := \frac{Z0L - Z1L}{3 \cdot Z1L}$

$\underline{Isa} := Ia + k0 \cdot Ir$ $\underline{Isb} := Ib + k0 \cdot Ir$ $\underline{Isc} := Ic + k0 \cdot Ir$

$Ua_k := \text{submatrix}(Va, k \cdot 8, k \cdot 8 + \text{wind}, 0, 0)$ $Ub_k := \text{submatrix}(Vb, k \cdot 8, k \cdot 8 + \text{wind}, 0, 0)$ $Uc_k := \text{submatrix}(Vc, k \cdot 8, k \cdot 8 + \text{wind}, 0, 0)$

$Ao_k := \text{submatrix}(Ir, k \cdot 8, k \cdot 8 + \text{wind}, 0, 0)$

$Aa_k := \text{submatrix}(Isa, k \cdot 8, k \cdot 8 + \text{wind}, 0, 0)$ $Ab_k := \text{submatrix}(Isb, k \cdot 8, k \cdot 8 + \text{wind}, 0, 0)$ $Ac_k := \text{submatrix}(Isc, k \cdot 8, k \cdot 8 + \text{wind}, 0, 0)$

$\underline{Pa}_k := \text{FFT}(Ua_k)$ $\underline{Pb}_k := \text{FFT}(Ub_k)$ $\underline{Pc}_k := \text{FFT}(Uc_k)$

$\underline{Fa}_k := \text{FFT}(Aa_k)$ $\underline{Fb}_k := \text{FFT}(Ab_k)$ $\underline{Fc}_k := \text{FFT}(Ac_k)$ $\underline{Fo}_k := \text{FFT}(Ao_k)$

2.2. TESTING THE PATENTED ALGORITHM

Initial assumptions:

- Faulted phase is known (a)

- Phase voltage (V_{sa}) during the fault is measured

$$\underline{V_{sa_k}} := (P_{a_k})_{1,0}$$

- Phase currents (I_{sabc}) during the fault are measured

$$\underline{I_{sa_k}} := (F_{a_k})_{1,0}$$

$$\underline{I_{sb_k}} := (F_{b_k})_{1,0}$$

$$\underline{I_{sc_k}} := (F_{c_k})_{1,0}$$

Line parameters needed in patented algorithm:

$$\underline{Z_{laa}} := ZL_{0,0}$$

$$\underline{Z_{lab}} := ZL_{0,1}$$

$$\underline{Z_{lac}} := ZL_{0,2}$$

$$\underline{Z_{raa}} := ZR_{0,0}$$

$$\underline{Z_{rab}} := ZR_{0,1}$$

$$\underline{Z_{rac}} := ZR_{0,2}$$

Defining $C1$ and $C2$:

$$\underline{C1_k} := Z_{laa} \cdot I_{sa_k} + Z_{lab} \cdot I_{sb_k} + Z_{lac} \cdot I_{sc_k}$$

$$\underline{C2_k} := Z_{raa} \cdot I_{sa_k} + Z_{rab} \cdot I_{sb_k} + Z_{rac} \cdot I_{sc_k}$$

Defining ar , ai , br , bi , cr , ci , dr and di :

$$\underline{ar_k} := \text{Re}(C1_k \cdot Z_{laa})$$

$$\underline{ai_k} := \text{Im}(C1_k \cdot Z_{laa})$$

$$\underline{br_k} := \text{Re}(V_{sa_k} \cdot Z_{laa} - C1_k \cdot Z_{laa} + C1_k \cdot Z_{raa})$$

$$\underline{bi_k} := \text{Im}(V_{sa_k} \cdot Z_{laa} - C1_k \cdot Z_{laa} + C1_k \cdot Z_{raa})$$

$$\underline{cr_k} := \text{Re}[Z_{raa} \cdot (V_{sa_k} - C1_k)]$$

$$\underline{ci_k} := \text{Im}[Z_{raa} \cdot (V_{sa_k} - C1_k)]$$

$$\underline{\underline{dr}}_k := \operatorname{Re}(Vsa_k - C1_k - C2_k)$$

$$\underline{\underline{di}}_k := \operatorname{Im}(Vsa_k - C1_k - C2_k)$$

Defining second degree polynomial coefficients (a, b and c):

$$\underline{\underline{a}}_k := ar_k - \frac{dr_k}{di_k} \cdot ai_k$$

$$a_{100} = 7.99 \times 10^6$$

$$\underline{\underline{b}}_k := br_k - \frac{dr_k}{di_k} \cdot bi_k$$

$$b_{100} = -5.362 \times 10^6$$

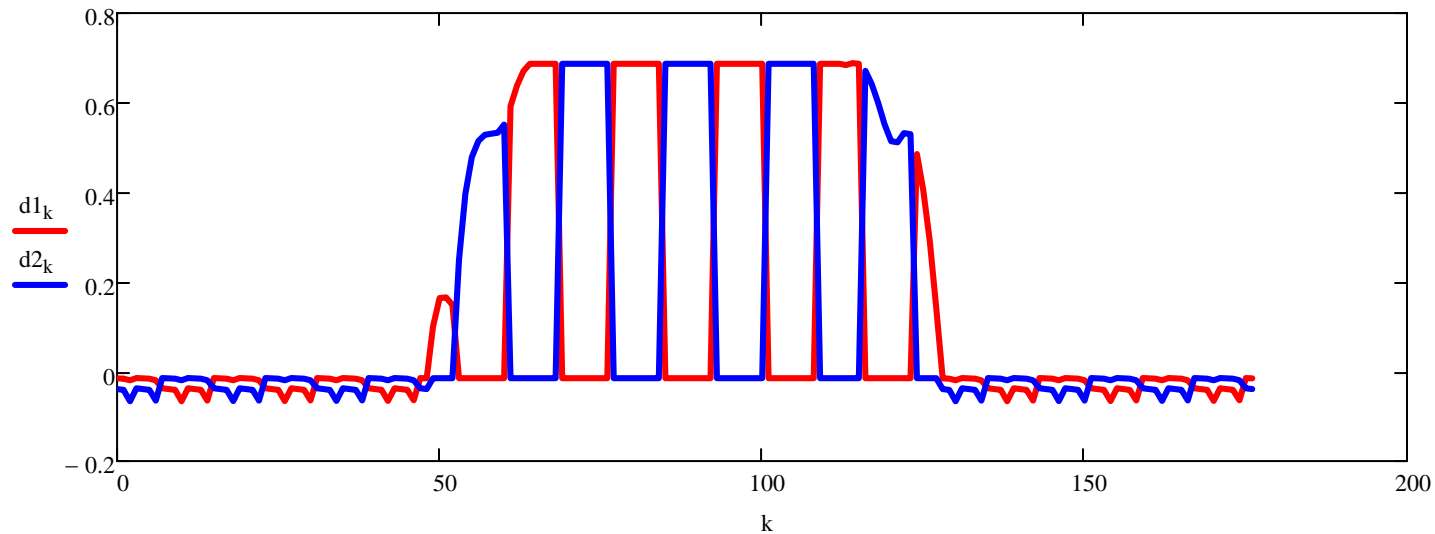
$$\underline{\underline{c}}_k := cr_k - \frac{dr_k}{di_k} \cdot ci_k$$

$$c_{100} = -8.438 \times 10^4$$

Solving the polynomial:

$$\underline{\underline{d1}}_k := \frac{-b_k + \sqrt{(b_k)^2 - 4 \cdot a_k \cdot c_k}}{2 \cdot a_k}$$

$$\underline{\underline{d2}}_k := \frac{(-b_k) - \sqrt{(b_k)^2 - 4 \cdot a_k \cdot c_k}}{2 \cdot a_k}$$



$$d1_{97} = 0.686$$

$$\text{calculated_fault_distance} := 1 - d1_{97}$$

$$\text{true_fault_distance} := M$$

calculated_fault_distance = 0.314

true_fault_distance = 0.5

ERROR := |calculated_fault_distance - true_fault_distance|

ERROR = 0.186

With the ideal 2-source data the patented algorithm performs quite poorly. The calculated fault distances are somewhat inaccurate. The results are most inaccurate when the fault is in the middle of the line. With small and large fault distances the error is smaller. See Table 1 for calculated fault distances when the actual fault distance varies.

From Table 1 we can also see that the modification to fault distance calculation proposed by Kim (fault distance = $2*(1-d)$) works only when the fault distance m is between 0 and 0.5

For fault distances larger than 0.5 the formula $1-d/2$ works better (doesn't work for distances smaller than 0.5).

The algorithm worked perfectly in Chapter 1, when it was tested with one time domain data (rms values). However, when digitalized values are used, the accuracy of this method is poor. Reason for this is unknown.

Table 1. Calculated fault distances

Actual fault distance	Calculated d	Calculated fault distance 1-d	error	Modification proposed by Kim, fault distance = $2*(1-d)$	error	Modification proposed by Mutanen, fault distance = $1-d/2$	error
0.05	0.976	0.024	0.026	0.047	0.003		
0.1	0.951	0.049	0.051	0.098	0.002		
0.3	0.835	0.165	0.135	0.329	0.029		
0.5	0.686	0.314	0.186	0.627	0.127		
0.7	0.488	0.512	0.188	1.024	0.324	0.756	0.056
0.9	0.208	0.792	0.108	1.583	0.683	0.896	0.004
0.95	0.118	0.882	0.068	1.763	0.813	0.941	0.004

I was unable to test the patented algorithm with the real fault data, because the impedance Z_R is unknown for the CreelmanN system. (I don't even know if the Creelman system is a 2- or 1-source system)